


<b>Search Notes</b>  	<b>Application/Control No.</b>  10597554	<b>Applicant(s)/Patent Under Reexamination</b>  BEIKIRCH ET AL.
	<b>Examiner</b>  RANDOLPH CHU	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
382/181, 190, 193-195, 197, 199, 202, 166	2/16/2011	ric
Inventor Name Search	2/16/2011	ric
EAST	2/16/2011	ric
Consult with Wenpeng Chen	2/16/2011	ric
NPL, Internet	2/16/2011	ric

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	PG Pub, UPAD Text search, see interference search print out	2/16/2011	ric

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